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| FORM PTO-1449 (Modified) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary) | ATTY. DOCKET NO. | SERIAL NO. |
| | BUR920030080US1 | 10/595,526 |
| | APPLICANT: Leah Pastel | |
| | FILING DATE: | GROUP: |
| | 4-26-06 | 2829 |

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

| EXAMINER INITIALS | | DOCUMENT NUMBER | ISSUED DATE | NAME | CLASS | SUBCLASS | FILING DATE (IF APPRO.) |
|----------------------|----|--------------------|----------------|----------------|-------|----------|----------------------------|
| | A1 | 6043672 | 03-28-00 | Sugasawara | | | |
| | A2 | 5757203 | 05-26-98 | Brown | | | |
| | A3 | 5742177 | 04-21-98 | Kalb, Jr. | | | |
| | A4 | 5726997 | 03-10-98 | Teene | | | |
| | A5 | 5670890 | 09-23-97 | Colwell et al | | | |
| | A6 | 5371457 | 12-06-94 | Lipp | | | |
| | A7 | 6538314 | 03-25-03 | Buffet et al | | | |
| | A8 | 6342790 | 01-29-02 | Ferguson et al | | | |
| | A9 | 6118293 | 09-12-00 | Manhaeve et al | | | |
| | B1 | 5917331 | 06-29-99 | Persons | | | |
| | B2 | 5721495 | 02-24-98 | Jennion et al | | | |
| | B3 | 5773990 | 06-30-98 | Wilstrup et al | | | |

FOREIGN PATENT DOCUMENTS

| | | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION | |
|--|----|-----------------|------|---------|-------|----------|-------------|----|
| | | | | | | | YES | NO |
| | B4 | | | | | | | |
| | B5 | | | | | | | |
| | B6 | | | | | | | |

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

| | |
|----|--|
| C1 | IBM Technical Disclosure Bulletin, Vol. 28, No.1, June 1985, Bossen, et al, "Yield and Reliability Enhancement Via Redundancy for VLSI Chips And Wafers", pp 36-42 |
| C2 | IBM Technical Disclosure Bulletin, Vol. 20, No.11A, April 1978, Fox, et al, "Flexible Voltage Distribution In Custom Semiconductor Circuit Chips", pp 4378-4379 |

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| EXAMINER | /Roberto Velez/ | DATE CONSIDERED | 10/09/2008 |
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.